

Claims 1-11 and 16-18 are now in the application. Claims 1, and 8 have been amended, and claim 15 has been cancelled.

In item 2 on page 2 of the Office action, claims 1-7 have been rejected as being anticipated by Kuriyama (5,682,057) under 35 U.S.C. § 102.

Claim 1 has been amended to better define the invention.

Support for the change regarding the protective structure can be found by referring to the specification at page 2, lines 4-13, and at page 12, lines 13-17. Support for the limitation, "subsequent to connecting the terminal of the first integrated circuit to the terminal of the package, severing the electrically conductive connection between the terminal and the signal terminal of the first integrated circuit using an energy pulse" can be found by referring to the specification at page 11, lines 17-18, and at page 12, line 19 through page 14, line 16.

Claim 1 now specifies steps of:

providing a protective structure that becomes conductive to dissipate electrostatic discharges; and

providing a second integrated circuit having a terminal that is coupled to the protective structure.

The intermediate narrow portion 10C of the conductor strip 10 of the fuse element 7 taught by the reference is not a protective structure that becomes conductive to dissipate electrostatic discharges. In fact the reference does not teach or suggest anything regarding a protective structure that becomes conductive to dissipate electrostatic discharges.

Claim 3 even further distinguishes the invention from the prior art by defining steps of providing a protective structure that becomes conductive and forming the electrically conductive connection with a portion of the providing reduced cross sectional area.

The Examiner has referred to the intermediate narrow portion 10C of the conductor strip 10 of the fuse element 7 taught by the reference and has used that feature to satisfy the limitations concerning the portion of reduced cross sectional area and the protective structure that were previously defined by claim 3.

However, the steps of providing a protective structure that becomes conductive to dissipate electrostatic discharges and forming the electrically conductive connection with a portion of reduced cross sectional area cannot both be met by the fuse element 7.

In item 3 on page 2 of the Office action, claims 1 and 15-18 have been rejected as being anticipated by Ma (6,054,334) under 35 U.S.C. § 102.

Claim 1 as now defined is not anticipated because it includes steps of:

connecting the terminal of the first integrated circuit to a terminal of a package; and

subsequent to connecting the terminal of the first integrated circuit to the terminal of the package, severing the electrically conductive connection between the terminal and the signal terminal of the first integrated circuit using an energy pulse.

Ma teaches a method for testing an embedded memory array 4 of an embedded chip product 2 that includes logic circuitry 6 as well as the embedded memory array 4. The testing is performed after the embedded memory array 4 is constructed but before construction of the logic circuitry 6 is completed (See column 1, lines 33-50, for example). It should be clear that the severing step taught by Ma is performed before further processing of the logic circuitry 6 and before the embedded chip product 2 is connected to a pin or a pad of a package.

For example, Ma teaches performing an etching step to separate the intermediate probe pad 12 from the lead 14 (column 4, line 66 through column 5, line 23).

In item 5 on page 3 of the Office action, claims 8-10 have been rejected as being obvious over Kuriyama (5,682,057) in view of Bozso (5,760,478) under 35 U.S.C. § 103.

Claim 8 has been amended to better define the invention. Support for the changes can be found by referring to the specification at page 2, lines 4-13, and at page 12, lines 13-17.

Claim 8 now defines steps of:

providing a protective structure that becomes conductive to dissipate electrostatic discharges; and

electrically coupling at least the first terminal pad of the second integrated circuit to the protective structure.

The intermediate narrow portion 10C of the conductor strip 10 of the fuse element 7 taught by the reference is not a protective structure that becomes conductive to dissipate electrostatic discharges. In fact the reference does not

teach or suggest anything regarding a protective structure that becomes conductive to dissipate electrostatic discharges.

It is accordingly believed to be clear that none of the references, whether taken alone or in any combination, either show or suggest the features of claims 1 or 8. Claims 1 and 8 are, therefore, believed to be patentable over the art and since all of the dependent claims are ultimately dependent on claim 1 or 8, they are believed to be patentable as well.

In view of the foregoing, reconsideration and allowance of claims 1-11 and 16-18 are solicited.

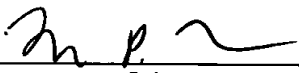
In the event the Examiner should still find any of the claims to be unpatentable, he is respectfully requested to telephone counsel so that, if possible, patentable language can be worked out.

Petition for extension is herewith made. The extension fee for response within a period of two months pursuant to Section 1.136(a) in the amount of 390.00 in accordance with Section 1.17 is enclosed herewith.

Please charge any other fees which might be due with respect to Sections 1.16 and 1.17 to the Deposit Account of Lerner and

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Respectfully submitted,



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